OMB No. 0651-0011

INFORMATION DISCLOSURE CITATION

Atty. Docket No.	0673.0070-00	Serial No.	10/062,714
Applicant	Ming-Dou KER, et al.		
Filing Date	February 5, 2002	Group:	2811

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Examiner Victor A. Mandala Gr | Date Considered 12-13-02

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